

ABSTRACT

APPARATUS FOR TESTING COMPUTER MEMORY

5 An electronic memory device tester has an input  
arranged to receive seed data with a first number (p)  
of seed data bits from a computer and a data generator  
arranged to receive an array of prepared data having a  
second number (q) of prepared data bits, where  $q > p$ , and  
10 arrange to generate from the prepared data a test data  
pattern for writing to an electronic memory device to  
be tested. The tester generates its own test pattern  
thus relieving the computer processor from that task.  
This in turn allows the computer to control the test  
15 cycle itself without compromising the test speed.

Figure 1 for Abstract

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